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APPLICATION NO. FILING DATE FIRST NAMED INVENTOR ATTORNEY DOCKET NO. CONFIRMATION NO. 09/729,833 12/06/2000 Pei-Ren Jeng 4425-090 5660 7590 07/25/2003 LOWE HAUPTMAN GILMAN & BERNER, LLP EXAMINER Suite 310 LEE, HSIEN MING 1700 Diagonal Road Alexandria, VA 22314 ART UNIT PAPER NUMBER 2823

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application N	0.	Applicant(s)	<del>(W</del>
<b>₩</b>		09/729,833		PEI-REN JENG	
Office Action Summary		Examiner		Art Unit	
		Hsien-Ming L	ee	2823	
Period fo	- The MAILING DATE of this communication				ess
A SHO THE N - Extens after S - If the - If NO - Failur - Any re	ORTENED STATUTORY PERIOD FOR REMAILING DATE OF THIS COMMUNICATION of time may be available under the provisions of 37 CF (SX (6) MONTHS from the mailing date of this communication period for reply specified above is less than thirty (30) days, period for reply is specified above, the maximum statutory period for reply within the set or extended period for reply will, by sply received by the Office later than three months after the new patent term adjustment. See 37 CFR 1.704(b).	DN. FR 1.136(a). In no event, ho n. a reply within the statutory r eriod will apply and will expi	wever, may a reply be tin ninimum of thirty (30) day re SIX (6) MONTHS from	nely filed  s will be considered timely. the mailing date of this comi	nunication.
1)⊠	Responsive to communication(s) filed on	<u>19 May 2003</u> .			
2a)⊠		This action is non	-final.		
3)  Disposition	Since this application is in condition for al closed in accordance with the practice un of Claims	llowance except for	formal matters, pr	rosecution as to the 453 O.G. 213.	merits is
4)🖂	Claim(s) 51-63 is/are pending in the applic	cation.			
4	4a) Of the above claim(s) is/are withdrawn from consideration.				
5) 🗌	Claim(s) is/are allowed.				
6)🖂	claim(s) <u>51-63</u> is/are rejected.				
7) 🗌 🖟	Claim(s) is/are objected to.				
8) 🗌 (	Claim(s) are subject to restriction a	nd/or election requi	rement.		
	on Papers				
9)∐ T	he specification is objected to by the Exan	niner.			
10)□ T	he drawing(s) filed on is/are: a)□ a	accepted or b)□ obje	cted to by the Exa	miner.	
	Applicant may not request that any objection	to the drawing(s) be h	eld in abeyance. S	ee 37 CFR 1.85(a).	
11)□ T	he proposed drawing correction filed on $\_$	is: a)□ appro	ved b)□ disappro	oved by the Examiner.	
	If approved, corrected drawings are required i	n reply to this Office a	action.		
12)∐ T	he oath or declaration is objected to by the	e Examiner.			
Priority u	nder 35 U.S.C. §§ 119 and 120				
13) 🗌 📝	Acknowledgment is made of a claim for for	eign priority under	35 U.S.C. § 119(a	)-(d) or (f).	
a)[	All b)☐ Some * c)☐ None of:				
•	I. Certified copies of the priority docum	nents have been red	ceived.		
2. Certified copies of the priority documents have been received in Application No					
	B. Copies of the certified copies of the application from the Internationate the attached detailed Office action for a	l Bureau (PCT Rule	: 17.2(a)).		age
14)□ Ad	knowledgment is made of a claim for dom	estic priority under	35 U.S.C. § 119(e	e) (to a provisional a	oplication).
a)	☐ The translation of the foreign language cknowledgment is made of a claim for dom	provisional applica	tion has been rec	eived.	,
Attachment(	5)				
2) Notice 3) Inform	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (PTO-948) ation Disclosure Statement(s) (PTO-1449) Paper Note		Notice of Informal F	/ (PTO-413) Paper No(s). Patent Application (PTO-1	
S. Patent and Tra- TO-326 (Rev.		e Action Summary		Part of Paper No. 12	

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### **DETAILED ACTION**

#### Remarks

1. The 112-second paragraph rejection to claim 62, 102(e) rejection to claims 51 and 63, 103(a) rejection to claims 52-62 are withdrawn.

## **Double Patenting**

2. The nonstatutory double patenting rejection is based on a judicially created doctrine grounded in public policy (a policy reflected in the statute) so as to prevent the unjustified or improper timewise extension of the "right to exclude" granted by a patent and to prevent possible harassment by multiple assignees. See *In re Goodman*, 11 F.3d 1046, 29 USPQ2d 2010 (Fed. Cir. 1993); *In re Longi*, 759 F.2d 887, 225 USPQ 645 (Fed. Cir. 1985); *In re Van Ornum*, 686 F.2d 937, 214 USPQ 761 (CCPA 1982); *In re Vogel*, 422 F.2d 438, 164 USPQ 619 (CCPA 1970); and, *In re Thorington*, 418 F.2d 528, 163 USPQ 644 (CCPA 1969).

A timely filed terminal disclaimer in compliance with 37 CFR 1.321(c) may be used to overcome an actual or provisional rejection based on a nonstatutory double patenting ground provided the conflicting application or patent is shown to be commonly owned with this application. See 37 CFR 1.130(b).

Effective January 1, 1994, a registered attorney or agent of record may sign a terminal disclaimer. A terminal disclaimer signed by the assignee must fully comply with 37 CFR 3.73(b).

3. Claims 51-63 are rejected under the judicially created doctrine of obviousness-type double patenting as being unpatentable over claims 14, 17, 18, 20, 21, 24-27 of U.S. Patent No. 6,372,660 in view of Muller (US 6,207,517) and Wu (US 6,127,247).

Although the conflicting claims are not identical, they are not patentably distinct from each other because both the Patent and the instant invention claim common subject matters, regardless of obvious variations as explained as follow.

In re claims 51 and 63, US '660 claims the claimed method for forming a dual damascene opening, comprising the steps as recited in claim 14; and further claims "etching through said second dielectric layer and said first dielectric layer until surface of said substrate is exposed by said dense region as an etched barrier layer to patterning said dual damascene", as recited in

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claim 24. The subject matter of recitation in claim 24 is equivalent to the "performing" step in claim 51 of the instant invention. In re claim 63, US '660 also claim forming a hard mask layer on said dielectric layer (claim 27, line 44).

Although the Patent does not expressly claim that "the etching rate of said dense region is lower than said second portion of said dielectric layer", it would have been obvious to one of the ordinary skill in the art, at the time the invention was made, to comprehend that using "dense region as an etched barrier" (claim 24, line 22, the Patent) implies that "the etching rate of said dense region is lower than said second portion of said dielectric layer"; otherwise the "dense region" cannot act as "etched barrier."

In re claim 52, US '660 does not claim that "the process of implanting comprises a retrograde implantation."

Muller, however, in an analogous art of forming a dense region in a dielectric layer teaches: providing a substrate 10 (Fig.1a); forming the dielectric layer 20 on the substrate 19 (Fig.1a); providing a first photoresist layer 30 on the dielectric layer 20 (Fig.1b); implanting ions I by using the first photoresist layer 30 as a mask to form the dense (implanted) region 40 (Fig.1b); and removing the first photoresist layer 30 (Fig.1c; col. 4, lines 62-63); in which a multiple implantation process is used in the method including three ion implantation steps I1, I2 and I3 into the dielectric layer 20 with gradually increasing implantation concentration profile (col.5, lines 23-28) as shown in Fig. 2. The dopant used in the multiple implantation process would include a P or B ion (col.2, lines 40-44). The multiple implantation process of Muller is a retrograde implantation process (col. 6, lines 33-34).

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Therefore, it would have been obvious to one of ordinary skill in the art, at the time the invention was made, to utilize the retrograde implantation of Muller in the implanting step of US '660 for forming the dense region, since by doing so it would be able to weaken bond structure, which is beneficial to subsequently etching the dense region (col.5, lines 7-11, Muller).

In re claims 53-61, US '660 claims that the implanting comprises a first ion implantation process with a first energy between 20 to 100 KeV (claim 21), the implantation dosage is  $10^{12}$   $\sim 10^{15}$  atoms/cm<sup>2</sup> (claim 17), the first ion comprises a boron or a phosphorous ion (claims 18 and 20) but does not claim the energies for a second and third implantation.

Wu, however, in a retrograde implantation process teaches that the first, second and third energies are  $100 \sim 1,000$  KeV (col.4, lines 36-42), 500 KeV  $\sim$  5MeV (col.5, lines 15-16) and 200 KeV  $\sim$  3MeV (col. Lines 5, lines 24-25), respectively; and the first, second and third implantation doses are  $10^{12}$  atoms/cm<sup>2</sup>  $\sim$   $10^{13}$  atoms/cm<sup>2</sup> (col.4, line42), 5 x  $10^{11}$  atoms/cm<sup>2</sup>  $\sim$   $10^{15}$  atoms/cm<sup>2</sup> (col.5, lines 16-17) and  $10^{12}$  atoms/cm<sup>2</sup>  $\sim$  5 x  $10^{13}$  atoms/cm<sup>2</sup> (col.5, lines 25-26), respectively.

Therefore, it would have been obvious to one of the ordinary skill in the art, at the time the invention was made, to utilize the specific energies and doses as taught by Wu in the retrograde implantation of US'660 in view of Muller, since by doing it would eliminate additional masking layer for the implantation and avoid outgassing issue in the convention process (col.3, lines 1-3, Wu), which, in turn, would reduce manufacturing cost (col.2, lines 16-21, Wu).

In re claim 62, the selection of the etched selectivity between the dense region and the dielectric layer is obvious to one of the ordinary skill in the art because it is a matter of

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determining optimum process condition by routine experimentation to selectively etch the predetermined etched region without damaging rest portions of the dielectric layer. In this case, the originally filed specification fails to demonstrate the criticality as to why the etched selectivity has to be about 2 for achieving <u>unexpected</u> results. See M.P.E.P. 2144.05 III.

#### Conclusion

4. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Hsien-Ming Lee whose telephone number is 703-305-7341. The examiner can normally be reached on M-F (9:00  $\sim$  5:00).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Olik Chaudhuri can be reached on 703-306-2794. The fax phone numbers for the

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organization where this application or proceeding is assigned are 703-308-7722 for regular communications and 703-308-7722 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

Hsien-Ming Lee Examiner

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July 23, 2003

W. DAVID COLEMAN PRIMARY EXAMINER